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| <b>Search Notes</b><br><br> | <b>Application/Control No.</b><br><br>10598934 | <b>Applicant(s)/Patent Under Reexamination</b><br><br>NAKAHATA ET AL. |
|  | <b>Examiner</b><br><br>SELIM AHMED             | <b>Art Unit</b><br><br>2826   |

| SEARCHED |              |          |          |
|----------|--------------|----------|----------|
| Class    | Subclass     | Date     | Examiner |
| 257      | 13, 103      | 12/13/08 | /sa/     |
| 438      | 46, 483, 481 | 12/13/08 | /sa/     |

| SEARCH NOTES   |          |          |
|--|----------|----------|
| Search Notes   | Date     | Examiner |
| Text search such as, Group III, III-V, nitride, GaN,GaInN, GaAlN, InGaN, AlGaIn, separate/sever/cleave/lasing/etching, substrate, crystal, nuclei/nucleus, seed, orientation, face, orientation, angle, degree,and their boolean combinations were searched. | 12/13/08 | /sa/     |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

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